

# MC33771B\_SDS

## Battery cell controller IC

Rev. 6.0 — 22 June 2020

Product short data sheet

## 1 General description

---

The 33771 is a SMARTMOS lithium-ion battery cell controller IC designed for automotive applications, such as hybrid electric (HEV) and electric vehicles (EV) along with industrial applications, such as energy storage systems (ESS) and uninterruptible power supply (UPS) systems.

The device performs ADC conversions of the differential cell voltages and current, as well as battery coulomb counting and battery temperature measurements. The information is digitally transmitted through the Serial Peripheral Interface (SPI) or Transformer Isolation (TPL) to a microcontroller for processing.

## 2 Features

---

- $9.6\text{ V} \leq V_{PWR} \leq 61.6\text{ V}$  operation, 75 V transient
- 7 to 14 cells management
- Isolated 2.0 Mbps differential communication or 4.0 Mbps SPI
- Addressable on initialization
- 0.8 mV maximum total voltage measurement error
- Synchronized cell voltage/current measurement with coulomb count
- Total stack voltage measurement
- Seven GPIO/temperature sensor inputs
- 5.0 V at 5.0 mA reference supply output
- Automatic over/undervoltage and temperature detection routable to fault pin
- Integrated sleep mode over/undervoltage and temperature monitoring
- Onboard 300 mA passive cell balancing with diagnostics
- Hot plug capable
- Detection of internal and external faults, as open lines, shorts, and leakages
- Designed to support ISO 26262, up to ASIL D safety system
- Fully compatible with the MC33772 for a maximum of six cells
- Qualified in compliance with AEC-Q100



3 Simplified application diagram

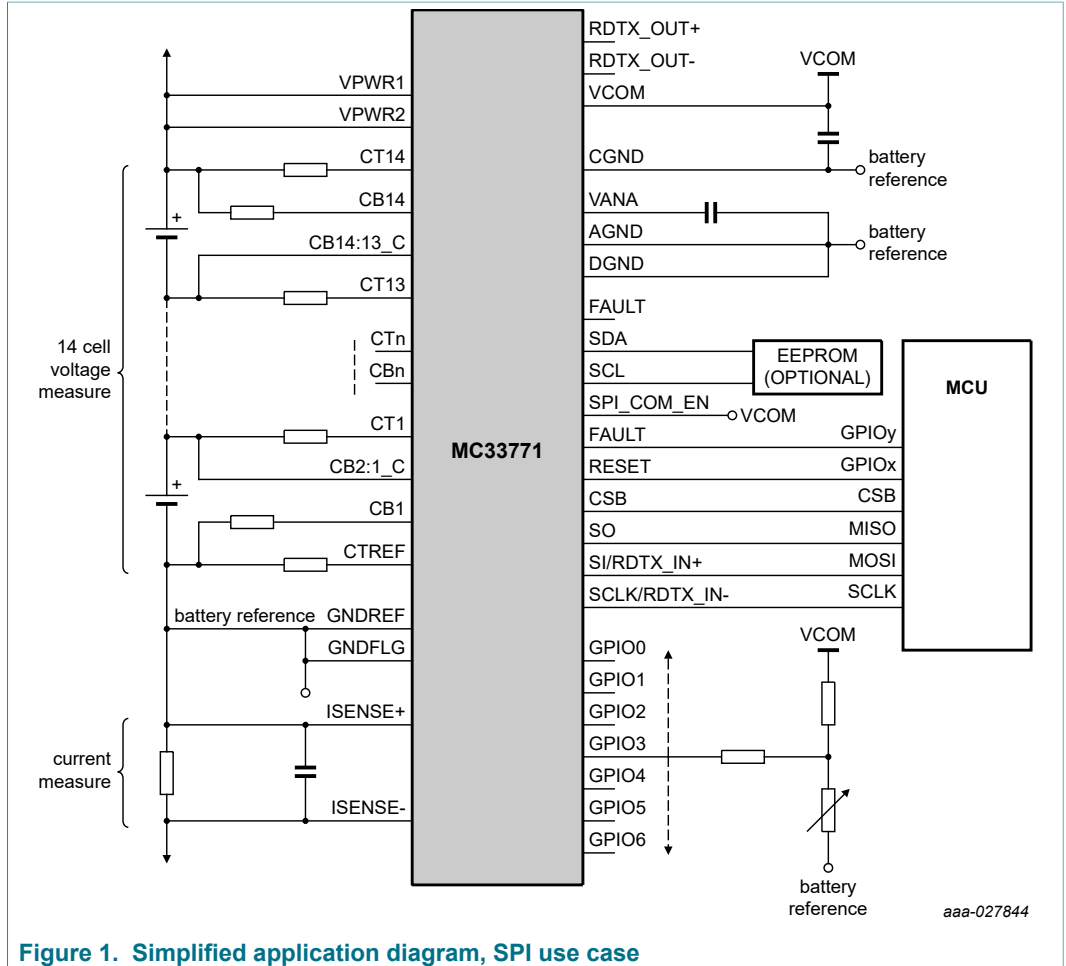
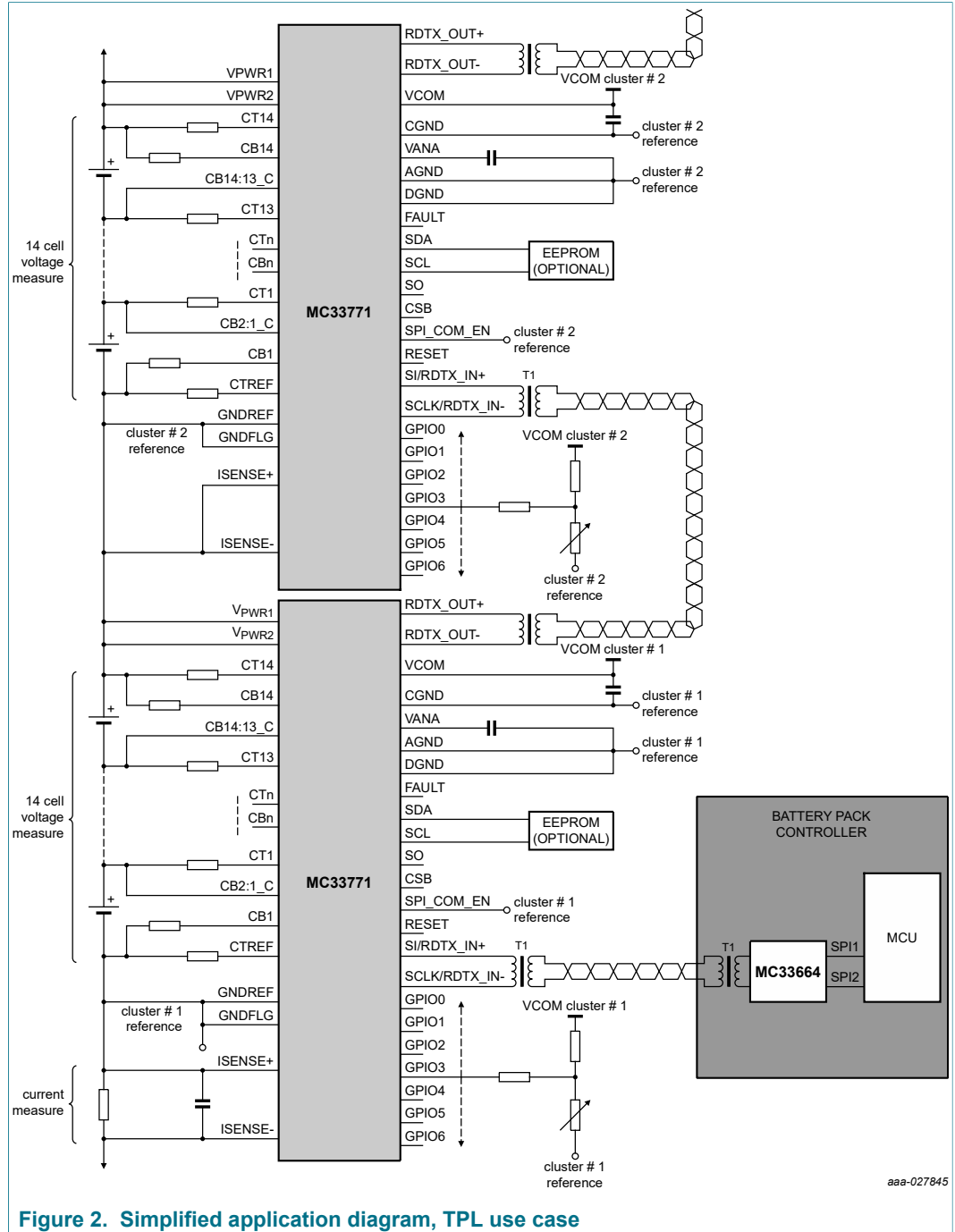


Figure 1. Simplified application diagram, SPI use case



## 4 Applications

- Automotive: 48 V and high-voltage battery packs
- E-bikes, e-scooters
- Energy storage systems
- Uninterruptible power supply (UPS)

## 5 Ordering information

### 5.1 Part numbers definition

## MC33771B x y z AE/R2

Table 1. Part number breakdown

Code	Option	Description
x	S	x = S (SPI communication type)
	T	x = T (TPL communication type)
y	A	y = A (Advanced)
	B	y = B (Basic)
	P	y = P (Premium)
z	1	z = 1 (7 to 14 channels)
	2	z = 2 (7 to 8 channels)
	AE	Package suffix
	R2	Tape and reel indicator

## 5.2 Part numbers list

This section describes the part numbers available to be purchased along with their differences. Valid orderable part numbers are provided on the web. To determine the orderable part numbers for this device, go to <http://www.nxp.com>.

**Table 2. Advanced orderable part table**

Temperature range is  $-40$  to  $105$  °C

Package type is 64-pin LQFP-EP

Orderable part	Number of channels	OV/UV	Precision GPIO as temperature channels and OT/UT	Current channel or coulomb count
<b>SPI communication protocol</b>				
MC33771BSA1AE	7 to 14	Yes	Yes	No
MC33771BSA2AE	7 to 8	Yes	Yes	No
<b>TPL differential communication protocol</b>				
MC33771BTA1AE	7 to 14	Yes	Yes	No
MC33771BTA2AE	7 to 8	Yes	Yes	No

**Table 3. Basic orderable part table**

Temperature range is  $-40$  to  $105$  °C

Package type is 64-pin LQFP-EP

Orderable part	Number of channels	OV/UV	Precision GPIO as temperature channels and OT/UT	Current channel or coulomb count
<b>SPI communication protocol</b>				
MC33771BSB1AE	7 to 14	Yes	No	No
MC33771BSB2AE	7 to 8	Yes	No	No
<b>TPL differential communication protocol</b>				
MC33771BTB1AE	7 to 14	Yes	No	No
MC33771BTB2AE	7 to 8	Yes	No	No

**Table 4. Premium orderable part table**

Temperature range is  $-40$  to  $105$  °C

Package type is 64-pin LQFP-EP

Orderable part	Number of channels	OV/UV	Precision GPIO as temperature channels and OT/UT	Current channel or coulomb count
<b>SPI communication protocol</b>				
MC33771BSP1AE	7 to 14	Yes	Yes	Yes
MC33771BSP2AE	7 to 8	Yes	Yes	Yes
<b>TPL differential communication protocol</b>				
MC33771BTP1AE	7 to 14	Yes	Yes	Yes
MC33771BTP2AE	7 to 8	Yes	Yes	Yes

## 6 Pinning information

### 6.1 Pinout diagram

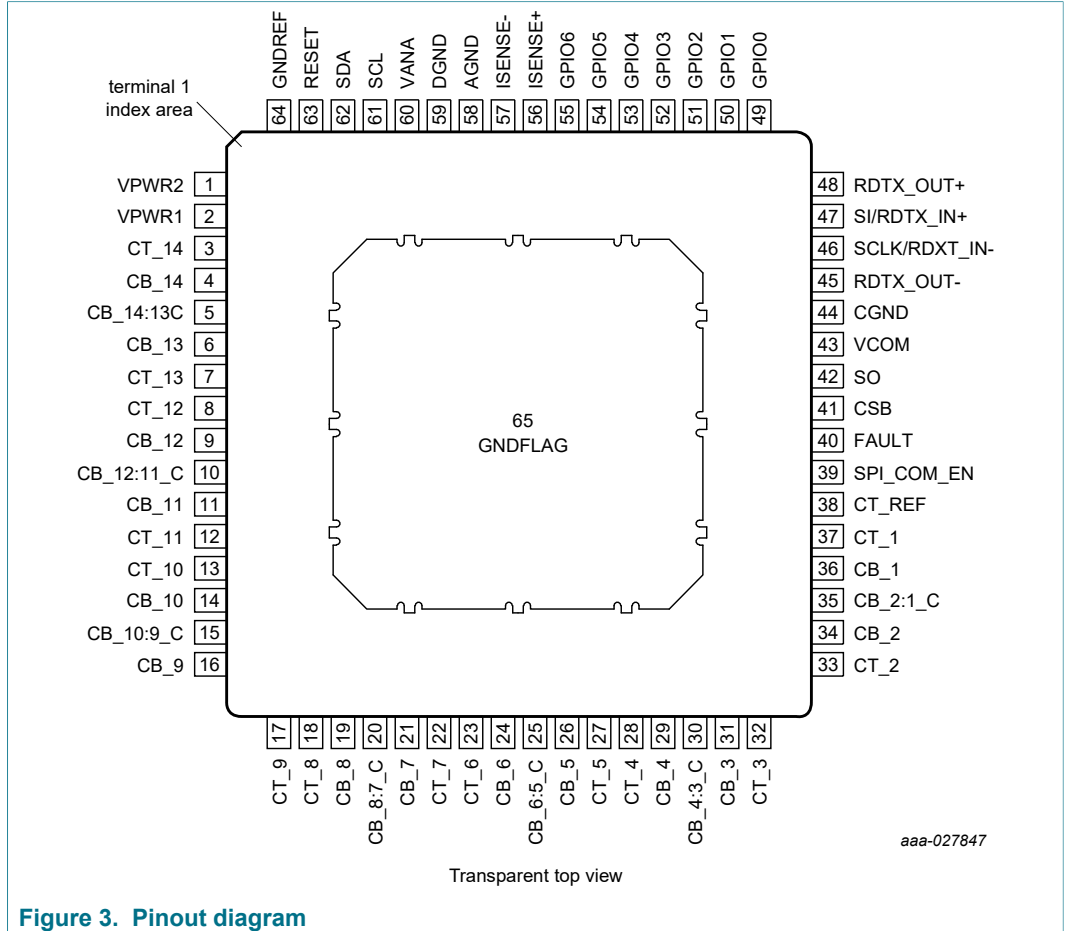


Figure 3. Pinout diagram

### 6.2 Pin definitions

Table 5. Pin definitions

Number	Name	Function	Definition
1	VPWR2	Input	Power input to the 33771
2	VPWR1	Input	Power input to the 33771
3	CT_14	Input	Cell pin 14 input. Terminate to LPF resistor.
4	CB_14	Output	Cell balance driver. Terminate to cell 14 cell balance load resistor.
5	CB_14:13_C	Output	Cell balance 14:13 common. Terminate to cell 14 and 13 common pin.
6	CB_13	Output	Cell balance driver. Terminate to cell 13 cell balance load resistor.
7	CT_13	Input	Cell pin 13 input. Terminate to LPF resistor.
8	CT_12	Input	Cell pin 12 input. Terminate to LPF resistor.

Number	Name	Function	Definition
9	CB_12	Output	Cell balance driver. Terminate to cell 12 cell balance load resistor.
10	CB_12:11_C	Output	Cell balance 12:11 common. Terminate to cell 12 and 11 common pin.
11	CB_11	Output	Cell balance driver. Terminate to cell 11 cell balance load resistor.
12	CT_11	Input	Cell pin 11 input. Terminate to LPF resistor.
13	CT_10	Input	Cell pin 10 input. Terminate to LPF resistor.
14	CB_10	Output	Cell balance driver. Terminate to cell 10 cell balance load resistor.
15	CB_10:9_C	Output	Cell balance 10:9 common. Terminate to cell 10 and 9 common pin.
16	CB_9	Output	Cell balance driver. Terminate to cell 9 cell balance load resistor.
17	CT_9	Input	Cell pin 9 input. Terminate to LPF resistor.
18	CT_8	Input	Cell pin 8 input. Terminate to LPF resistor.
19	CB_8	Output	Cell balance driver. Terminate to cell 8 cell balance load resistor.
20	CB_8:7_C	Output	Cell balance 8:7 common. Terminate to cell 8 and 7 common pin.
21	CB_7	Output	Cell balance driver. Terminate to cell 7 cell balance load resistor.
22	CT_7	Input	Cell pin 7 input. Terminate to LPF resistor.
23	CT_6	Input	Cell pin 6 input. Terminate to LPF resistor.
24	CB_6	Output	Cell balance driver. Terminate to cell 6 cell balance load resistor.
25	CB_6:5_C	Output	Cell balance 6:5 common. Terminate to cell 6 and 5 common pin.
26	CB_5	Output	Cell balance driver. Terminate to cell 5 cell balance load resistor.
27	CT_5	Input	Cell pin 5 input. Terminate to LPF resistor.
28	CT_4	Input	Cell pin 4 input. Terminate to LPF resistor.
29	CB_4	Output	Cell balance driver. Terminate to cell 4 cell balance load resistor.
30	CB_4:3_C	Output	Cell balance 4:3 common. Terminate to cell 4 and 3 common pin.
31	CB_3	Output	Cell balance driver. Terminate to cell 3 cell balance load resistor.
32	CT_3	Input	Cell pin 3 input. Terminate to LPF resistor.
33	CT_2	Input	Cell pin 2 input. Terminate to LPF resistor.
34	CB_2	Output	Cell balance driver. Terminate to cell 2 cell balance load resistor.

Number	Name	Function	Definition
35	CB_2:1_C	Output	Cell Balance 2:1 common. Terminate to cell 2 and 1 common pin.
36	CB_1	Output	Cell balance driver. Terminate to cell 1 cell balance load resistor.
37	CT_1	Input	Cell pin 1 input. Terminate to LPF resistor.
38	CT_REF	Input	Cell pin REF input. Terminate to LPF resistor.
39	SPI_COM_EN	Input	SPI communication enable, pin must be high for the SPI to be active
40	FAULT	Output	Fault output dependent on user defined internal or external faults. If not used, it must be left open.
41	CSB	Input	SPI chip select
42	SO	Output	SPI serial output
43	VCOM	Output	Communication regulator output. Decouple with 2.2 $\mu$ F ceramic.
44	CGND	Ground	Communication decoupling ground. Terminate to GNDREF
45	RDTX_OUT-	I/O	Receive/transmit output negative
46	SCLK/RDTX_IN-	I/O	SPI clock or receive/transmit input negative
47	SI/RDTX_IN+	I/O	SPI serial input or receiver/transmit input positive
48	RDTX_OUT+	I/O	Receive/transmit output positive
49	GPIO0	I/O	General purpose analog input or GPIO or wake-up or fault daisy chain
50	GPIO1	I/O	General purpose analog input or GPIO
51	GPIO2	I/O	General purpose analog input or GPIO or conversion trigger
52	GPIO3	I/O	General purpose analog input or GPIO
53	GPIO4	I/O	General purpose analog input or GPIO
54	GPIO5	I/O	General purpose analog input or GPIO
55	GPIO6	I/O	General purpose analog input or GPIO
56	ISENSE+	Input	Current measurement input+
57	ISENSE-	Input	Current measurement input-
58	AGND	Ground	Analog ground, terminate to GNDREF
59	DGND	Ground	Digital ground, terminate to GNDREF
60	VANA	Output	Precision ADC analog supply. Decouple with ceramic 47 nF ceramic capacitor to AGND.
61	SCL	I/O	I <sup>2</sup> C clock
62	SDA	I/O	I <sup>2</sup> C data



Number	Name	Function	Definition
63	RESET	Input	RESET is an active high input. RESET has an internal pull down. If not used, it can be tied to GND.
64	GNDREF	Ground	Ground reference for device. Terminate to reference of battery cluster.
65	GNDFLAG	Ground	Device flag. Terminate to lowest potential of battery cluster.

## 7 General product characteristics

### 7.1 Ratings and operating requirements relationship

The operating voltage range pertains to the VPWR pins referenced to the AGND pins.

Table 6. Ratings vs. operating requirements

Fatal range • Permanent failure might occur	Handling range – no permanent failure			Fatal range • Permanent failure might occur
	Lower limited operating range • No permanent failure, but IC functionality is not guaranteed	Normal operating range • 100 % functional	Upper limited operating range • IC parameters might be out of specification • Detection of V <sub>PWR</sub> overvoltage is functional	
V <sub>PWR</sub> < -0.3 V	7.6 V ≤ V <sub>PWR</sub> < 9.6 V <b>Reset range:</b> -0.3 V ≤ V <sub>PWR</sub> < 7.6 V	9.6 V ≤ V <sub>PWR</sub> ≤ 61.6 V	61.6 V < V <sub>PWR</sub> ≤ 75 V	75 V < V <sub>PWR</sub>

In both upper and lower limited operating range, no information can be provided about IC performance. Only the detection of V<sub>PWR</sub> overvoltage is guaranteed in the upper limited operating range.

Performance in normal operating range is guaranteed only if there is a minimum of seven battery cells in the stack.

### 7.2 Maximum ratings

Table 7. Maximum ratings

All voltages are with respect to ground unless otherwise noted. Exceeding these ratings may cause a malfunction or permanent damage to the device.

Symbol	Description (rating)	Min	Max	Unit
<b>Electrical ratings</b>				
VPWR1, VPWR2	Supply input voltage	-0.3	75	V
CT14	Cell terminal voltage	-0.3	75	V
VPWR to CT14	Voltage across VPWR1,2 pins pair and CT14 pin	-10	10.5	V
CT <sub>N</sub> to CT <sub>N-1</sub>	Cell terminal differential voltage	[1] -0.3	6.0	V
CT <sub>N(CURRENT)</sub>	Cell terminal input current	—	±500	µA
CB <sub>N</sub> to CB <sub>N:N-1_C</sub> CB <sub>N:N-1_C</sub> to CB <sub>N-1</sub>	Cell balance differential voltage	—	10	V
CB <sub>N-1_C</sub> to CT <sub>N-1</sub>	Cell balance input to cell terminal input	-10	+10	V

Symbol	Description (rating)	Min	Max	Unit
VISENSE	ISENSE+ and ISENSE- pin voltage	-0.3	2.5	V
VCOM	Maximum voltage may be applied to VCOM pin from external source	—	5.8	V
VANA	Maximum voltage may be applied to VANA pin	—	3.1	V
VGPIO0	GPIO0 pin voltage	-0.3	6.5	V
VGPIOx	GPIOx pins (x = 1 to 6) voltage	-0.3	VCOM + 0.5	V
VDIG	Voltage I <sup>2</sup> C pins (SDA, SCL)	-0.3	VCOM + 0.5	V
VRESET	RESET pin	-0.3	6.5	V
VCSB	CSB pin	-0.3	6.5	V
VSPI_COMM_EN	SPI_COMM_EN	-0.3	6.5	V
VSO	SO pin	-0.3	VCOM + 0.5	V
VGPIO5,6	Maximum voltage for GPIO5 and GPIO6 pins used as current input	-0.3	2.5	V
FAULT	Maximum applied voltage to pin	-0.3	7.0	V
VCOMM	Maximum voltage to pins RDTX_OUT+, RDTX_OUT-, SI/RDTX_IN+, CLK/RDTX_IN-	-10.0	10.0	V
f <sub>SPI</sub>	SPI frequency (SPI mode)	—	4.2	MHz
BR <sub>TPL</sub>	Transformer communication bit rate (TPL mode)	1.9	2.1	Mbps
f <sub>TPL</sub>	Transformer signal frequency (TPL mode)	3.8	4.2	MHz
V <sub>ESD</sub>	ESD voltage Human body model (HBM) Charge device model (CDM) Charge device model corner pins (CDM)	— — —	±2000 ±500 ±750	V
V <sub>ESD</sub>	ESD voltage (VPWR1, VPWR2, CTx, CBx, GPIOx, ISENSE+, ISENSE-, RDTX_OUT+, RDTX_OUT-, SI/RDTX_IN+, SCLK/RDTX_IN-) Human body model (HBM) <sup>[2]</sup>	—	±4000	V
V <sub>ESD</sub>	ESD voltage (CTREF, CTx, CBx, GPIOx, ISENSE+, ISENSE-, RDTX_OUT+, RDTX_OUT-, SI/RDTX_IN+, SCLK/RDTX_IN-) IEC 61000-4-2, Unpowered (Gun configuration: 330Ω / 150pF) HMM, Unpowered (Gun configuration: 330Ω / 150pF) ISO 10605:2009, Unpowered (Gun configuration: 2 kΩ / 150pF) ISO 10605:2009, Powered (Gun configuration: 2 kΩ / 150pF)	— — — —	±8000 ±8000 ±8000 ±8000	V

[1] Adjacent CT pins may experience an overvoltage that exceeds their maximum rating during OV/UV functional verification test or during open line diagnostic test. Nevertheless, the IC is completely tolerant to this special situation.

[2] ESD testing is performed in accordance with the human body model (HBM) (C<sub>ZAP</sub> = 100 pF, R<sub>ZAP</sub> = 1500 Ω), and the charge device model (CDM) (C<sub>ZAP</sub> = 4.0 pF).

### 7.3 Thermal characteristics

**Table 8. Thermal ratings**

All voltages are with respect to ground unless otherwise noted. Exceeding these ratings may cause a malfunction or permanent damage to the device.

Symbol	Description (rating)	Min	Max	Unit
<b>Thermal ratings</b>				
T <sub>A</sub> T <sub>J</sub>	Operating temperature			°C
	Ambient	-40	+105	
	Junction	-40	+150	
T <sub>STG</sub>	Storage temperature	-55	+150	°C
T <sub>PPRT</sub>	Peak package reflow temperature	[1] [2]	260	°C
<b>Thermal resistance and package dissipation ratings</b>				
R <sub>ΘJB</sub>	Junction-to-board (bottom exposed pad soldered to board) 64 LQFP EP	[3]	10	°C/W
R <sub>ΘJA</sub>	Junction-to-ambient, natural convection, single-layer board (1s) 64 LQFP EP	[4] [5]	59	°C/W
R <sub>ΘJA</sub>	Junction-to-ambient, natural convection, four-layer board (2s2p) 64 LQFP EP	[4] [5]	27	°C/W
R <sub>ΘJCTOP</sub>	Junction-to-case top (exposed pad) 64 LQFP EP	[6]	14	°C/W
R <sub>ΘJCBOTTOM</sub>	Junction-to-case bottom (exposed pad) 64 LQFP EP	[7]	0.97	°C/W
Ψ <sub>JT</sub>	Junction to package top, natural convection	[8]	3	°C/W

- [1] Pin soldering temperature limit is for 10 seconds maximum duration. Not designed for immersion soldering. Exceeding these limits may cause a malfunction or permanent damage to the device.
- [2] NXP's Package Reflow capability meets Pb-free requirements for JEDEC standard J-STD-020C. For Peak Package Reflow Temperature and Moisture Sensitivity Levels (MSL), go to [www.nxp.com](http://www.nxp.com), search by part number (remove prefixes/suffixes) and enter the core ID to view all orderable parts (MC33xxx enter 33xxx), and review parametrics.
- [3] Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
- [4] Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
- [5] Per JEDEC JESD51-6 with the board (JESD51-7) horizontal.
- [6] Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1), with the cold plate temperature used for the case temperature.
- [7] Thermal resistance between the die and the solder pad on the bottom of the package based on simulation without any interface resistance.
- [8] Thermal characterization parameter indicating the temperature difference between the package top and the junction temperature per JEDEC JESD51-2. When Greek letter (Ψ) is not available, the thermal characterization parameter is written as Psi-JT.

### 7.4 Electrical characteristics

**Table 9. Static and dynamic electrical characteristics**

Characteristics noted under conditions 9.6 V ≤ V<sub>PWR</sub> ≤ 61.6 V, -40 °C ≤ T<sub>A</sub> ≤ 105 °C, GND = 0 V, unless otherwise stated. Typical values refer to V<sub>PWR</sub> = 56 V, T<sub>A</sub> = 25 °C, unless otherwise noted.

Symbol	Parameter	Min	Typ	Max	Unit
<b>Power management</b>					
V <sub>PWR(FO)</sub>	Supply voltage Full parameter specification	9.6	—	61.6	V

Symbol	Parameter	Min	Typ	Max	Unit
I <sub>VPWR</sub>	Supply current (base value) Normal mode, cell balance OFF, ADC inactive, SPI communication inactive, IVCOM = 0 mA	—	5.4	—	mA
	Normal mode, cell balance OFF, ADC inactive, TPL communication inactive, IVCOM = 0 mA	—	8.0	—	
I <sub>VPWR(TPL_TX)</sub>	Supply current adder when TPL communication active	—	50	—	mA
I <sub>VPWR(CBON)</sub>	Supply current adder to set all 14 cell balance switches ON	—	0.97	—	mA
I <sub>VPWR(ADC)</sub>	Delta supply current to perform ADC conversions (addend) ADC1-A,B continuously converting ADC2 continuously converting	—	3.0	—	mA
		—	1.4	—	
I <sub>VPWR(SS)</sub>	Supply current in sleep mode and in idle mode, communication inactive, cell balance off, cyclic measurement off, oscillator monitor on				μA
	SPI mode (25 °C)	—	40	—	
	TPL mode (25 °C)	—	68	—	
I <sub>VPWR(CKMON)</sub>	Clock monitor current consumption	—	5	—	μA
V <sub>PWR(OV_FLAG)</sub>	V <sub>PWR</sub> overvoltage fault threshold (flag)	—	65	—	V
V <sub>PWR(LV_FLAG)</sub>	V <sub>PWR</sub> low-voltage warning threshold (flag)	—	12	—	V
V <sub>PWR(UV_POR)</sub>	V <sub>PWR</sub> undervoltage shutdown threshold (POR)	—	8.5	—	V
V <sub>PWR(HYS)</sub>	V <sub>PWR</sub> UV hysteresis voltage	—	200	—	mV
t <sub>VPWR(FILTER)</sub>	V <sub>PWR</sub> OV, LV filter	—	50	—	μs
<b>VCOM power supply</b>					
V <sub>COM</sub>	VCOM output voltage	—	5.0	—	V
I <sub>VCOM</sub>	VCOM output current allocated for external use	—	—	5.0	mA
V <sub>COM(UV)</sub>	VCOM undervoltage fault threshold	—	4.4	—	V
V <sub>COM_HYS</sub>	VCOM undervoltage hysteresis	—	100	—	mV
t <sub>VCOM(FLT_TIMER)</sub>	VCOM undervoltage fault timer	—	10	—	μs
t <sub>VCOM(RETRY)</sub>	VCOM fault retry timer	—	10	—	ms
V <sub>COM(OV)</sub>	VCOM overvoltage fault threshold	5.4	—	5.9	V
I <sub>LIM(OC)</sub>	VCOM current limit	65	—	140	mA
R <sub>VCOM(SS)</sub>	VCOM sleep mode pull-down resistor	—	2.0	—	kΩ
<b>VANA power supply</b>					
V <sub>ANA</sub>	VANA output voltage (not used by external circuits) Decouple with 47 nF X7R 0603 or 0402	—	2.65	—	V
V <sub>ANA(UV)</sub>	VANA undervoltage fault threshold	—	2.4	—	V
V <sub>ANA_HYS</sub>	VANA undervoltage hysteresis	—	50	—	mV
V <sub>ANA(FLT_TIMER)</sub>	VANA undervoltage fault timer	—	11	—	μs
V <sub>ANA(OV)</sub>	VANA overvoltage fault threshold	—	2.8	—	V
t <sub>VANA(RETRY)</sub>	VANA fault retry timer	—	10	—	ms
I <sub>LIM(OC)</sub>	VANA current limit	5.0	—	10	mA
R <sub>VANA_RPD</sub>	VANA sleep mode pull-down resistor	—	1.0	—	kΩ
t <sub>VANA</sub>	VANA rise time (CL = 47 nF ceramic X7R only)	—	—	100	μs
<b>ADC1-A, ADC1-B</b>					

Symbol	Parameter	Min	Typ	Max	Unit
CTn <sub>(LEAKAGE)</sub>	Cell terminal input leakage current (except in SLEEP mode when cell balancing is ON)	—	10	—	nA
CTn <sub>(FV)</sub>	Cell terminal input current - functional verification	—	0.365	—	mA
CT <sub>N</sub>	Cell terminal input current during conversion	—	50	—	nA
R <sub>PD</sub>	Cell terminal open load detection pull-down resistor	—	950	—	Ω
V <sub>VPWR_RES</sub>	VPWR terminal measurement resolution	—	2.44141	—	mV/LSB
V <sub>VPWR_RNG</sub>	VPWR terminal measurement range	9.6	—	75	V
VPWR <sub>TERM_ERR</sub>	VPWR terminal measurement accuracy	-0.5	—	0.5	%
V <sub>CT_RNG</sub>	ADC differential input voltage range for CTn to CTn-1	0.0	—	4.85	V
V <sub>CT_ANx_RES</sub>	Cell voltage and ANx resolution in 15-bit MEAS_xxxx registers	—	152.58789	—	μV/LSB
V <sub>ERR33RT</sub>	Cell voltage measurement error V <sub>CELL</sub> = 3.3 V, T <sub>A</sub> = 25 °C	-0.8	±0.4	0.8	mV
V <sub>ERR</sub>	Cell voltage measurement error 0.1 V ≤ V <sub>CELL</sub> ≤ 4.8 V, -40 °C ≤ T <sub>A</sub> ≤ 105 °C (or -40 °C ≤ T <sub>J</sub> ≤ 125 °C)	—	±0.7	—	mV
V <sub>ERR_1</sub>	Cell voltage measurement error 0 V ≤ V <sub>CELL</sub> ≤ 1.5 V, -40 °C ≤ T <sub>A</sub> ≤ 60 °C (or -40 °C ≤ T <sub>J</sub> ≤ 85 °C)	—	±0.4	—	mV
V <sub>ERR_2</sub>	Cell voltage measurement error 1.5 V ≤ V <sub>CELL</sub> ≤ 2.7 V, -40 °C ≤ T <sub>A</sub> ≤ 60 °C (or -40 °C ≤ T <sub>J</sub> ≤ 85 °C)	—	±0.4	—	mV
V <sub>ERR_3</sub>	Cell voltage measurement error 2.7 V ≤ V <sub>CELL</sub> ≤ 3.7 V, -40 °C ≤ T <sub>A</sub> ≤ 60 °C (or -40 °C ≤ T <sub>J</sub> ≤ 85 °C)	—	±0.5	—	mV
V <sub>ERR_4</sub>	Cell voltage measurement error 3.7 V ≤ V <sub>CELL</sub> ≤ 4.3 V, -40 °C ≤ T <sub>A</sub> ≤ 60 °C (or -40 °C ≤ T <sub>J</sub> ≤ 85 °C)	—	±0.7	—	mV
V <sub>ERR_5</sub>	Cell voltage measurement error 1.5 V ≤ V <sub>CELL</sub> ≤ 4.5 V, -40 °C ≤ T <sub>A</sub> ≤ 105 °C (or -40 °C ≤ T <sub>J</sub> ≤ 125 °C)	—	±0.7	—	mV
V <sub>ANx_ERR</sub>	Magnitude of ANx error in the entire measurement range: Ratiometric measurement Absolute measurement after soldering and aging, input in the range [1.0, 4.5] V Absolute measurement after soldering and aging, input in the range [0, 4.85] V, for -40 °C < T <sub>A</sub> < 60 °C Absolute measurement after soldering and aging, input in the range [0, 4.85] V, for -40 °C < T <sub>A</sub> < 105 °C	— — -8.0 -11	— — — —	16 10 8.0 11	mV
t <sub>VCONV</sub>	Single channel net conversion time 13-bit resolution 14-bit resolution 15-bit resolution 16-bit resolution	— — — —	6.77 9.43 14.75 25.36	— — — —	μs
V <sub>V_NOISE</sub>	Conversion noise 13-bit resolution 14-bit resolution 15-bit resolution 16-bit resolution	— — — —	1800 1000 600 400	— — — —	μVrms
<b>ADC2/current sense module</b>					
V <sub>INC</sub>	I <sub>SENSE+</sub> /I <sub>SENSE-</sub> input voltage (reference to AGND)	-300	—	300	mV

Symbol	Parameter	Min	Typ	Max	Unit
V <sub>IND</sub>	ISENSE+/ISENSE- differential input voltage range	-150	—	150	mV
V <sub>ISENSEX(OFFSET)</sub>	ISENSE+/ISENSE- input voltage offset error	—	—	0.5	μV
I <sub>GAINERR</sub>	ISENSE error including nonlinearities	-0.5	—	0.5	%
I <sub>ISENSE_OL</sub>	ISENSE open load injected current	—	130	—	μA
V <sub>ISENSE_OL</sub>	ISENSE open load detection threshold	—	460	—	mV
V <sub>2RES</sub>	Current sense user register resolution	—	0.6	—	μV/LSB
V <sub>PGA_SAT</sub>	PGA saturation half-range				mV
	Gain = 256	—	4.9	—	
	Gain = 64	—	19.5	—	
	Gain = 16	—	78.1	—	
	Gain = 4	—	150.0	—	
V <sub>PGA_ITH</sub>	Voltage threshold for PGA gain increase				mV
	Gain = 256	—	—	—	
	Gain = 64	—	2.344	—	
	Gain = 16	—	9.375	—	
	Gain = 4	—	37.50	—	
V <sub>PGA_DTH</sub>	Voltage threshold for PGA gain decrease				mV
	Gain = 256	—	4.298	—	
	Gain = 64	—	17.188	—	
	Gain = 16	—	68.750	—	
	Gain = 4	—	—	—	
t <sub>AZC_SETTLE</sub>	Time to perform auto-zero procedure after enabling the current channel	—	200	—	μs
t <sub>ICONV</sub>	ADC conversion time including PGA settling time				μs
	13 bit resolution	—	19.00	—	
	14 bit resolution	—	21.67	—	
	15 bit resolution	—	27.00	—	
	16 bit resolution	—	37.67	—	
V <sub>I_NOISE</sub>	Noise error at 16-bit conversion	—	3.01	—	μVrms
V <sub>I_NOISE</sub>	Noise error at 13-bit conversion	—	8.33	—	μVrms
ADC <sub>CLK</sub>	ADC2 and ADC1-A,B clocking frequency	—	6.0	—	MHz
<b>Cell balance drivers</b>					
V <sub>DS(CLAMP)</sub>	Cell balance driver VDS active clamp voltage	—	11	—	V
V <sub>OUT(FLT_TH)</sub>	Output fault detection voltage threshold				V
	Balance off (open load)	—	0.55	—	
	Balance on (shorted load)	—	—	—	
R <sub>PD_CB</sub>	Output OFF open load detection pull-down resistor				kΩ
	Balance off, open load detect disabled	—	2.0	—	
I <sub>OUT(LKG)</sub>	Output leakage current				μA
	Balance off, open load detect disabled at V <sub>DS</sub> = 4.0 V	—	—	1.0	
R <sub>DS(on)</sub>	Drain-to-source on resistance				Ω
	I <sub>OUT</sub> = 300 mA, T <sub>J</sub> = 105 °C	—	—	0.80	
	I <sub>OUT</sub> = 300 mA, T <sub>J</sub> = 25 °C	—	0.5	—	
	I <sub>OUT</sub> = 300 mA, T <sub>J</sub> = -40 °C	—	0.4	—	
I <sub>LIM_CB</sub>	Driver current limitation (shorted resistor)	310	—	950	mA
t <sub>CB_AUTOP</sub>	CB_AUTO_PAUSE timing	—	4.0	—	μs
t <sub>ON</sub>	Cell balance driver turn on				μs
	R <sub>L</sub> = 15 Ω	—	350	—	

Symbol	Parameter	Min	Typ	Max	Unit
t <sub>OFF</sub>	Cell balance driver turn off R <sub>L</sub> = 15 Ω	—	200	—	μs
t <sub>BAL_DEGLICHTH</sub>	Short/open detect filter time	—	20	—	μs
<b>Internal temperature measurement</b>					
IC_TEMP1_ERR	IC temperature measurement error	-3.0	—	3.0	K
IC_TEMP1_RES	IC temperature resolution	—	0.032	—	K/LSB
TSD_TH	Thermal shutdown	—	170	—	°C
TSD_HYS	Thermal shutdown hysteresis	—	10	—	°C
<b>Default operational parameters</b>					
V <sub>CTOV(TH)</sub>	Cell overvoltage threshold (8 bits), typical value is default value after reset	0.0	4.2	5.0	V
V <sub>CTOV(RES)</sub>	Cell overvoltage threshold resolution	—	19.53125	—	mV/LSB
V <sub>CTUV(TH)</sub>	Cell undervoltage threshold (8 bits), typical value is default value after reset	0.0	2.5	5.0	V
V <sub>CTUV(RES)</sub>	Cell undervoltage threshold resolution	—	19.53125	—	mV/LSB
V <sub>GPIO_OT(TH)</sub>	GPIOx configured as ANx input overtemperature threshold from POR	—	1.16	—	V
V <sub>GPIO_OT(RES)</sub>	Temperature voltage threshold resolution	—	4.8828125	—	mV/LSB
V <sub>GPIO_UT(TH)</sub>	GPIOx configured as ANx input undertemperature threshold from POR	—	3.82	—	V
V <sub>GPIO_UT(RES)</sub>	Temperature voltage threshold resolution	—	4.8828125	—	mV/LSB
<b>General purpose input/output GPIOx</b>					
V <sub>IH</sub>	Input high-voltage (3.3 V compatible)	2.0	—	—	V
V <sub>IL</sub>	Input low-voltage (3.3 V compatible)	—	—	1.0	V
V <sub>HYS</sub>	Input hysteresis	—	100	—	mV
I <sub>IL</sub>	Input leakage current Pins tristate, V <sub>IN</sub> = V <sub>COM</sub> or AGND	-100	—	100	nA
I <sub>IDL</sub>	Differential Input Leakage Current GPIO 5,6 GPIO 5,6 configured as digital inputs for current measurement	-30	—	30	nA
V <sub>OH</sub>	Output high-voltage I <sub>OH</sub> = -0.5 mA	V <sub>COM</sub> - 0.8	—	—	V
V <sub>OL</sub>	Output low-voltage I <sub>OL</sub> = +0.5 mA	—	—	0.8	V
V <sub>ADC</sub>	Analog ADC input voltage range for ratiometric measurements	AGND	—	V <sub>COM</sub>	V
V <sub>OL(TH)</sub>	Analog input open pin detect threshold	—	0.15	—	V
R <sub>OPENPD</sub>	Internal open detection pull-down resistor	3.8	5.0	—	kΩ
t <sub>GPIO0_WU</sub>	GPIO0 WU de-glitch filter	—	50	—	μs
t <sub>GPIO0_FLT</sub>	GPIO0 daisy chain de-glitch filter both edges	—	20	—	μs
t <sub>GPIO2_SOC</sub>	GPIO2 convert trigger de-glitch filter	—	2.0	—	μs
t <sub>GPIOx_DIN</sub>	GPIOx configured as digital input de-glitch filter	2.5	—	5.6	μs
<b>Reset input</b>					
V <sub>IH_RST</sub>	Input high-voltage (3.3 V compatible)	2.0	—	—	V
V <sub>IL_RST</sub>	Input low-voltage (3.3 V compatible)	—	—	1.0	V
V <sub>HYS</sub>	Input hysteresis	—	0.6	—	V

Symbol	Parameter	Min	Typ	Max	Unit
t <sub>RESETFLT</sub>	RESET de-glitch filter	—	100	—	μs
R <sub>RESET_PD</sub>	Input logic pull down (RESET)	—	100	—	kΩ
<b>SPI_COM_EN input</b>					
V <sub>IH</sub>	Input high-voltage (3.3 V compatible)	2.0	—	—	V
V <sub>IL</sub>	Input low-voltage (3.3 V compatible)	—	—	1.0	V
V <sub>HYS</sub>	Input hysteresis	—	450	—	mV
R <sub>SPI_COM_EN_PD</sub>	Input pull-down resistor (SPI_COM_EN)	—	100	—	kΩ
<b>Bus switch for TPL communication</b>					
R <sub>XTERM</sub>	Bus termination resistor (open resistor when bus switch is closed)	—	150	—	Ω
Remark: If the bus switch is closed, then the termination resistor is open, else the termination resistor is connected. At the end of the daisy chain, the switch must be open, so that the transmission line is properly terminated.					
<b>Digital interface</b>					
V <sub>FAULT_HA</sub>	FAULT output (high active, IOH = 1.0 mA)	4.0	4.9	6.0	V
I <sub>FAULT_CL</sub>	FAULT output current limit	3.0	—	40	mA
R <sub>FAULT_PD</sub>	FAULT output pull-down resistance	—	100	—	kΩ
V <sub>IH_COMM</sub>	Voltage threshold to detect the input as high SI/RDTX_IN+, SCLK/RDTX_IN-, CSB, SDA, SCL (NOTE: needs to be 3.3 V compatible)	—	—	2.0	V
V <sub>IL_COMM</sub>	Voltage threshold to detect the input as low SI/RDTX_IN+, SCLK/RDTX_IN-, CSB, SDA, SCL	0.8	—	—	V
V <sub>HYS</sub>	Input hysteresis SI/RDTX_IN+, SCLK/RDTX_IN-, CSB, SDA, SCL	—	80	—	mV
I <sub>LOGIC_SS</sub>	Sleep state input logic current CSB	-100	—	100	nA
R <sub>SCLK_PD</sub>	Input logic pull-down resistance (SCLK/RDTX_IN-, SI/RDTX+)	—	20	—	kΩ
R <sub>I_PU</sub>	Input logic pull-up resistance to V <sub>COM</sub> (CSB, SDA, SCL)	—	100	—	kΩ
I <sub>SO_TRI</sub>	Tristate SO input current 0 V to V <sub>COM</sub>	-2.0	—	2.0	μA
V <sub>SO_HIGH</sub>	SO high-state output voltage with I <sub>SO(HIGH)</sub> = -2.0 mA	V <sub>COM</sub> - 0.4	—	—	V
V <sub>SO_LOW</sub>	SO, SDA, SLK low-state output voltage with I <sub>SO(HIGH)</sub> = -2.0 mA	—	—	0.4	V
CSB <sub>WU_FLT</sub>	CSB wake-up de-glitch filter, low to high transition	—	50	—	μs
<b>System timing</b>					
t <sub>CELL_CONV</sub>	Time needed to acquire all 14 cell voltages and the current after an on demand conversion 13-bit resolution 14-bit resolution 15-bit resolution 16-bit resolution	—	59 80 123 208	—	μs
t <sub>SYNC</sub>	V/I synchronization time ADC1-A,B at 13 bit, ADC2 at 13 bit ADC1-A,B at 14 bit, ADC2 at 13 bit ADC1-A,B at 15 bit, ADC2 at 13 bit ADC1-A,B at 16 bit, ADC2 at 13 bit	—	48.16 53.50 64.16 85.50	—	μs



Symbol	Parameter	Min	Typ	Max	Unit
t <sub>SYNC</sub>	V/I synchronization time	—	52.14	—	μs
	ADC1-A,B at 13 bit, ADC2 at 14 bit	—	57.48	—	
	ADC1-A,B at 14 bit, ADC2 at 14 bit	—	68.14	—	
	ADC1-A,B at 15 bit, ADC2 at 14 bit	—	89.48	—	
t <sub>SYNC</sub>	V/I synchronization time	—	62.12	—	μs
	ADC1-A,B at 13 bit, ADC2 at 15 bit	—	65.46	—	
	ADC1-A,B at 14 bit, ADC2 at 15 bit	—	76.12	—	
	ADC1-A,B at 15 bit, ADC2 at 15 bit	—	97.46	—	
t <sub>SYNC</sub>	V/I synchronization time	—	120.51	—	μs
	ADC1-A,B at 13 bit, ADC2 at 16 bit	—	117.84	—	
	ADC1-A,B at 14 bit, ADC2 at 16 bit	—	112.51	—	
	ADC1-A,B at 15 bit, ADC2 at 16 bit	—	113.39	—	
t <sub>VPWR(READY)</sub>	Time after VPWR connection for the IC to be ready for initialization	—	—	5.0	ms
t <sub>WAKE-UP</sub>	Sleep mode to normal mode device ready	—	—	400	μs
	Wake-up from fault	—	—	400	
	Wake-up from GPIO	—	—	400	
	Wake-up from network	—	—	400	
	Sleep mode to normal mode time after TPL bus wake-up	—	—	1.0	ms
t <sub>WAKE_DELAY</sub>	Time between wake pulses	—	600	—	μs
t <sub>IDLE</sub>	Idle timeout after POR	—	60	—	s
t <sub>WAKE_INIT</sub>	Wake-up signaling timeout after POR	—	0.65	—	s
t <sub>BALANCE</sub>	Cell balance timer range	0.5	—	511	min
t <sub>CYCLE</sub>	Cyclic acquisition timer range	0.0	—	8.5	s
t <sub>FAULT</sub>	Fault detection to activation of fault pin Normal mode	—	—	56	μs
t <sub>DIAG</sub>	Diagnostic mode timeout	0.047	1.0	8.5	s
t <sub>EOC</sub>	SOC to data ready (includes post processing of data)	—	148	—	μs
	13-bit resolution	—	201	—	
	14-bit resolution	—	307	—	
	15-bit resolution	—	520	—	
t <sub>SETTLE</sub>	Time after SOC to begin converting with ADC1-A,B	—	12.28	—	μs
t <sub>SYS_MEAS1</sub>	Time needed to send an SOC command and read back 96 cell voltages, 48 temperatures, 1 current, and 1 coulomb counter and ADC1-A,B configured as follows:	—	—	—	ms
	13-bit resolution	—	3.73	—	
	14-bit resolution	—	3.78	—	
	15-bit resolution	—	3.89	—	
	16-bit resolution	—	4.10	—	
t <sub>SYS_MEAS2</sub>	Time needed to send an SOC command and read back 96 cell voltages, 1 current, and 1 coulomb counter and ADC1-A,B configured as follows:	—	—	—	ms
	13-bit resolution	—	2.64	—	
	14-bit resolution	—	2.69	—	
	15-bit resolution	—	2.80	—	
	16-bit resolution	—	3.01	—	

Symbol	Parameter	Min	Typ	Max	Unit
t <sub>CLST_TPL</sub>	Time needed to send an SOC command and read back 14 cell voltages, 7 temperatures, 1 current, and 1 coulomb counter with TPL communication working at 2.0 Mbps and ADC1-A,B configured as follows:				ms
	13-bit resolution	—	0.79	—	
	14-bit resolution	—	0.85	—	
	15-bit resolution	—	0.95	—	
	16-bit resolution	—	1.16	—	
t <sub>CLST_SPI</sub>	Time needed to send an SOC command and read back 14 cell voltages, 7 temperatures, 1 current, and 1 coulomb counter with SPI communication working at 4.0 Mbps and ADC1-A,B configured as follows:				ms
	13-bit resolution	—	0.48	—	
	14-bit resolution	—	0.54	—	
	15-bit resolution	—	0.64	—	
	16-bit resolution	—	0.86	—	
t <sub>I2C_DOWNLOAD</sub>	Time to download EEPROM calibration after POR	—	—	1.0	ms
t <sub>I2C_ACCESS</sub>	EEPROM access time, EEPROM write (depends on device selection)	—	5.0	—	ms
t <sub>WAVE_DC_BITx</sub>	Daisy chain duty cycle off time t <sub>WAVE_DC_BITx</sub> = 00	—	500	—	µs
t <sub>WAVE_DC_BITx</sub>	Daisy chain duty cycle off time t <sub>WAVE_DC_BITx</sub> = 01	—	1.0	—	ms
t <sub>WAVE_DC_BITx</sub>	Daisy chain duty cycle off time t <sub>WAVE_DC_BITx</sub> = 10	—	10	—	ms
t <sub>WAVE_DC_BITx</sub>	Daisy chain duty cycle off time t <sub>WAVE_DC_BITx</sub> = 11	—	100	—	ms
t <sub>WAVE_DC_ON</sub>	Daisy chain duty cycle on time	—	500	550	µs
t <sub>COM_LOSS</sub>	Time out to reset the IC in the absence of communication	—	1024	—	ms
<b>SPI interface</b>					
f <sub>SCK</sub>	CLK/RDTX_IN- frequency <sup>[1]</sup>	—	—	4.0	MHz
t <sub>SCK_H</sub>	SCLK/RDTX_IN- high time (A) <sup>[1]</sup>	125	—	—	ns
t <sub>SCK_L</sub>	SCLK/RDTX_IN- high time (B) <sup>[1]</sup>	125	—	—	ns
t <sub>SCK</sub>	SCLK/RDTX_IN- period (A+B) <sup>[1]</sup>	250	—	—	ns
t <sub>FALL</sub>	SCLK/RDTX_IN- falling time	—	—	15	ns
t <sub>RISE</sub>	SCLK/RDTX_IN- rising time	—	—	15	ns
t <sub>SET</sub>	SCLK/RDTX_IN- setup time (O) <sup>[1]</sup>	20	—	—	ns
t <sub>HOLD</sub>	SCLK/RDTX_IN- hold time (P) <sup>[1]</sup>	20	—	—	ns
t <sub>SI_SETUP</sub>	SI/RDTX_IN+ setup time (F) <sup>[1]</sup>	40	—	—	ns
t <sub>SI_HOLD</sub>	SI/RDTX_IN+ hold time (G) <sup>[1]</sup>	40	—	—	ns
t <sub>SO_VALID</sub>	SO data valid, rising edge of SCLK/RDTX_IN- to SO data valid (I) <sup>[1]</sup>	—	—	40	ns
t <sub>SO_EN</sub>	SO enable time (H) <sup>[1]</sup>	—	—	40	ns
t <sub>SO_DISABLE</sub>	SO disable time (K) <sup>[1]</sup>	—	—	40	ns
t <sub>CSB_LEAD</sub>	CSB lead time (L) <sup>[1]</sup>	100	—	—	ns
t <sub>CSB_LAG</sub>	CSB lag time (M) <sup>[1]</sup>	100	—	—	ns
t <sub>TD</sub>	Sequential data transfer delay (N) <sup>[1]</sup>	1.0	—	—	µs

Symbol	Parameter	Min	Typ	Max	Unit
<b>TPL interface</b>					
V <sub>RDTX INTH</sub>	Differential receiver threshold	—	580	—	mV
V <sub>RDTX INHYS</sub>	Differential receiver threshold hysteresis	—	100	—	mV
t <sub>RES</sub>	Slave response after write command (echo)	—	2.35	—	µs

[1] See Figure 4

### 7.5 Timing diagrams

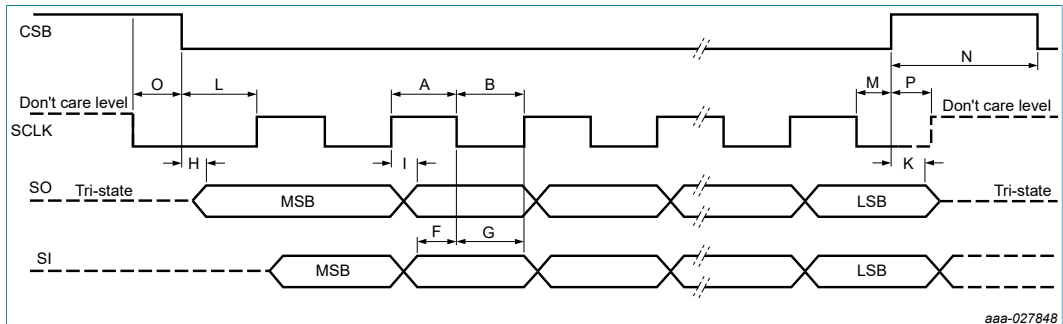


Figure 4. Low-voltage SPI interface timing

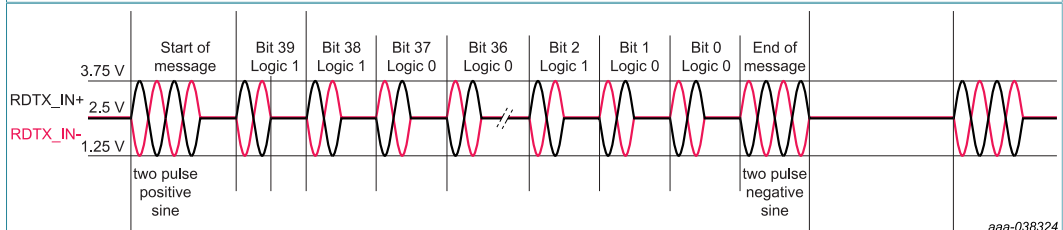


Figure 5. Transformer communication signaling

## 8 Packaging

### 8.1 Package mechanical dimensions

Package dimensions are provided in package drawings. To find the most current package outline drawing, go to [www.nxp.com](http://www.nxp.com) and perform a keyword search for the drawing's document number.

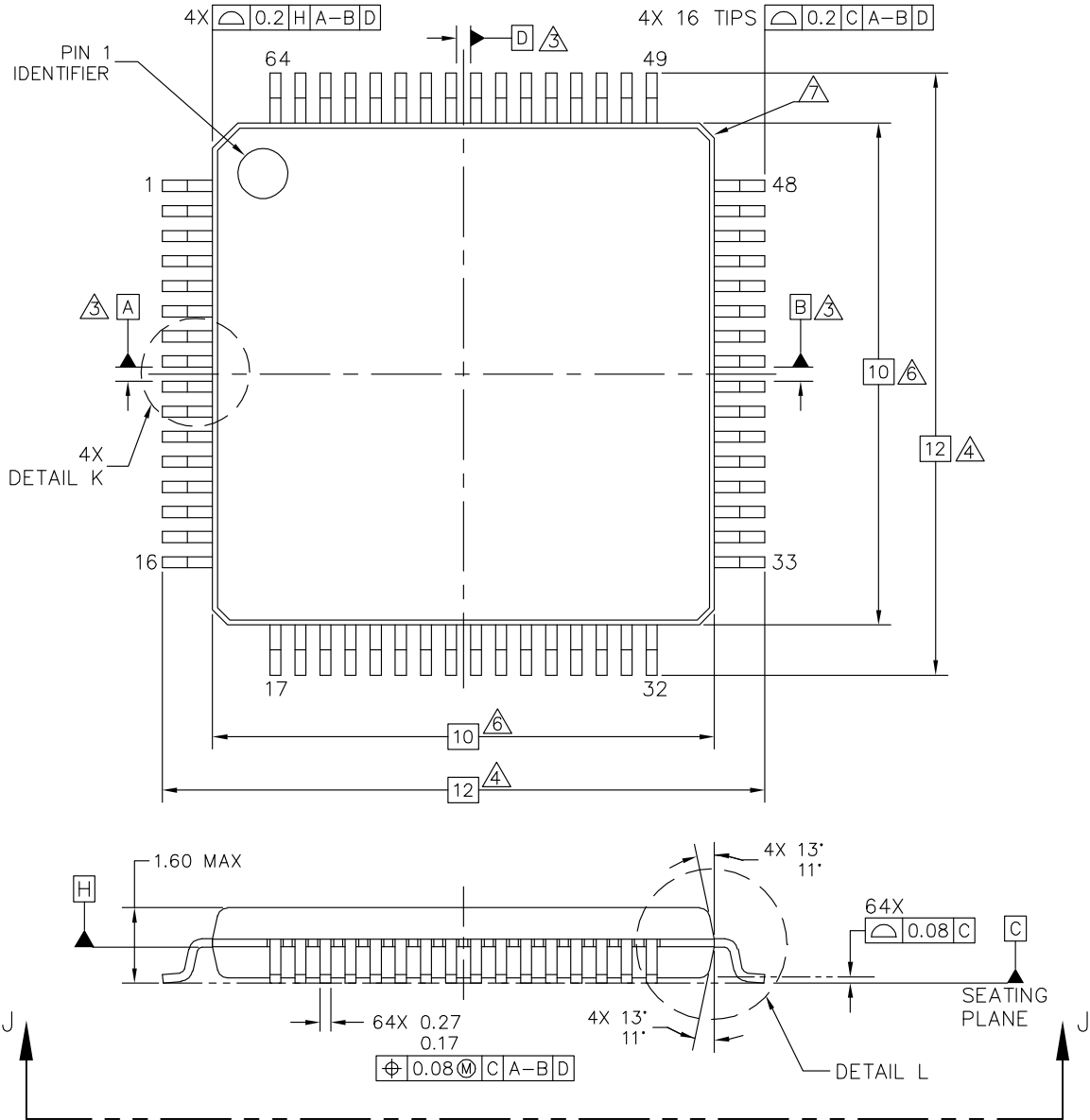
**Table 10. Package Outline**

Package	Suffix	Package outline drawing number
64-pin LQFP-EP	AE	98ASA10763D



© NXP SEMICONDUCTORS N.V. ALL RIGHTS RESERVED.  
ELECTRONIC VERSIONS ARE UNCONTROLLED EXCEPT WHEN  
ACCESSED DIRECTLY FROM THE DOCUMENT CONTROL REPOSITORY.  
PRINTED VERSIONS ARE UNCONTROLLED EXCEPT WHEN STAMPED  
"CONTROLLED COPY" IN RED.

MECHANICAL OUTLINE  
DO NOT SCALE THIS DRAWING



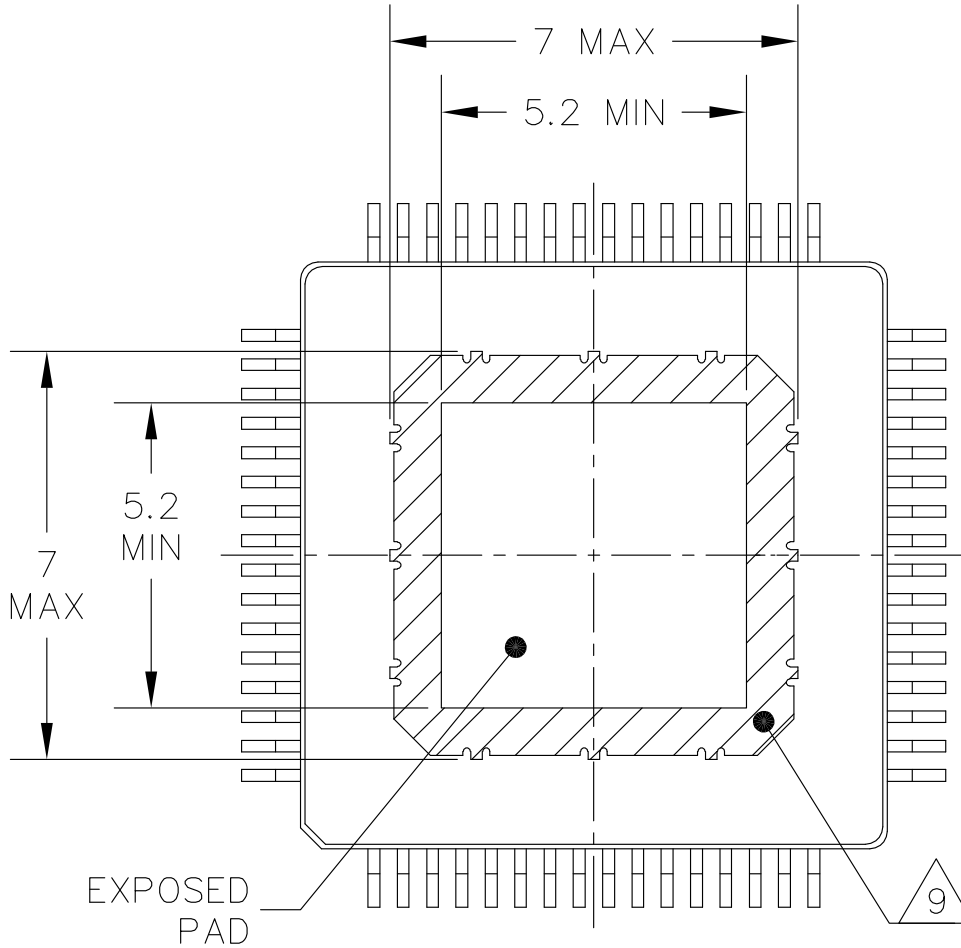
TITLE: LQFP, 10 X 10 X 1.4 PKG,  
0.5 PITCH, 64LD,  
6.1 x 6.1 EXPOSED PAD

DOCUMENT NO: 98ASA10763D	REV: D
STANDARD: JEDEC MS-026 BCD	
SOT1510-2	SHEET: 1 OF 5



© NXP SEMICONDUCTORS N.V. ALL RIGHTS RESERVED.  
ELECTRONIC VERSIONS ARE UNCONTROLLED EXCEPT WHEN  
ACCESSED DIRECTLY FROM THE DOCUMENT CONTROL REPOSITORY.  
PRINTED VERSIONS ARE UNCONTROLLED EXCEPT WHEN STAMPED  
"CONTROLLED COPY" IN RED.

MECHANICAL OUTLINE  
DO NOT SCALE THIS DRAWING



VIEW J-J

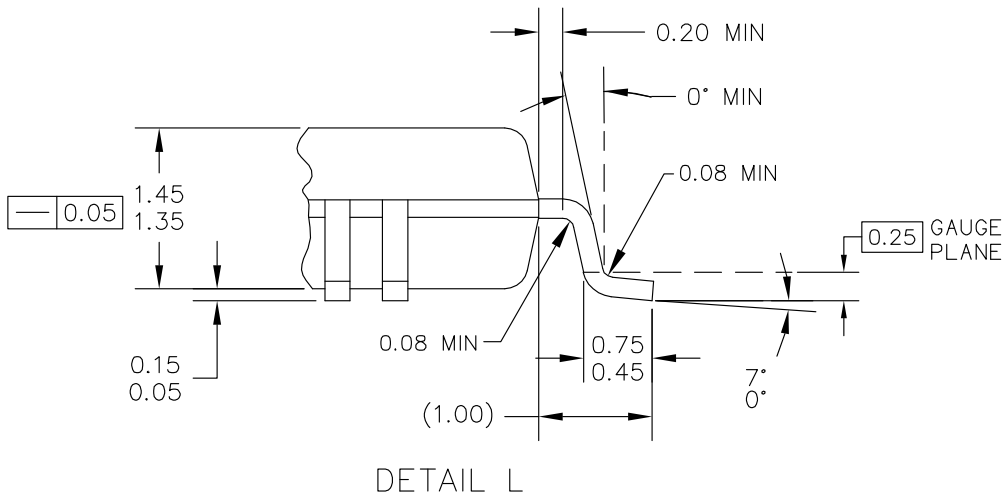
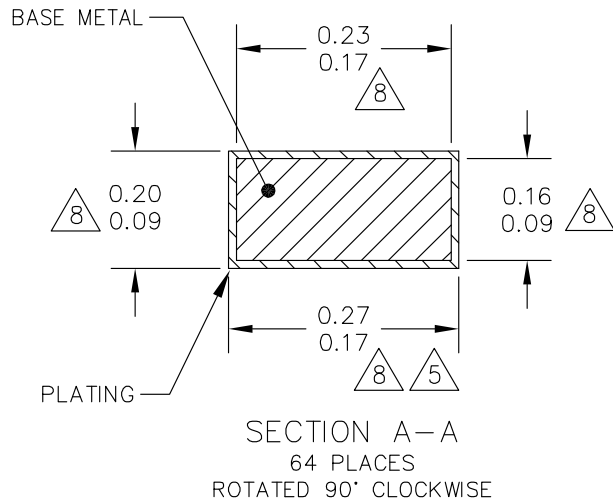
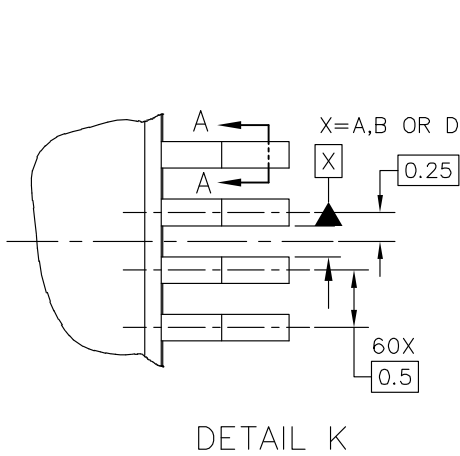
TITLE: LQFP, 10 X 10 X 1.4 PKG,  
0.5 PITCH, 64LD,  
6.1 x 6.1 EXPOSED PAD

DOCUMENT NO: 98ASA10763D	REV: D
STANDARD: JEDEC MS-026 BCD	
SOT1510-2	SHEET: 2



© NXP SEMICONDUCTORS N.V. ALL RIGHTS RESERVED.  
 ELECTRONIC VERSIONS ARE UNCONTROLLED EXCEPT WHEN  
 ACCESSED DIRECTLY FROM THE DOCUMENT CONTROL REPOSITORY.  
 PRINTED VERSIONS ARE UNCONTROLLED EXCEPT WHEN STAMPED  
 "CONTROLLED COPY" IN RED.

MECHANICAL OUTLINE  
 DO NOT SCALE THIS DRAWING



TITLE: LQFP, 10 X 10 X 1.4 PKG,  
 0.5 PITCH, 64LD,  
 6.1 x 6.1 EXPOSED PAD

DOCUMENT NO: 98ASA10763D	REV: D
STANDARD: JEDEC MS-026 BCD	
SOT1510-2	SHEET: 3

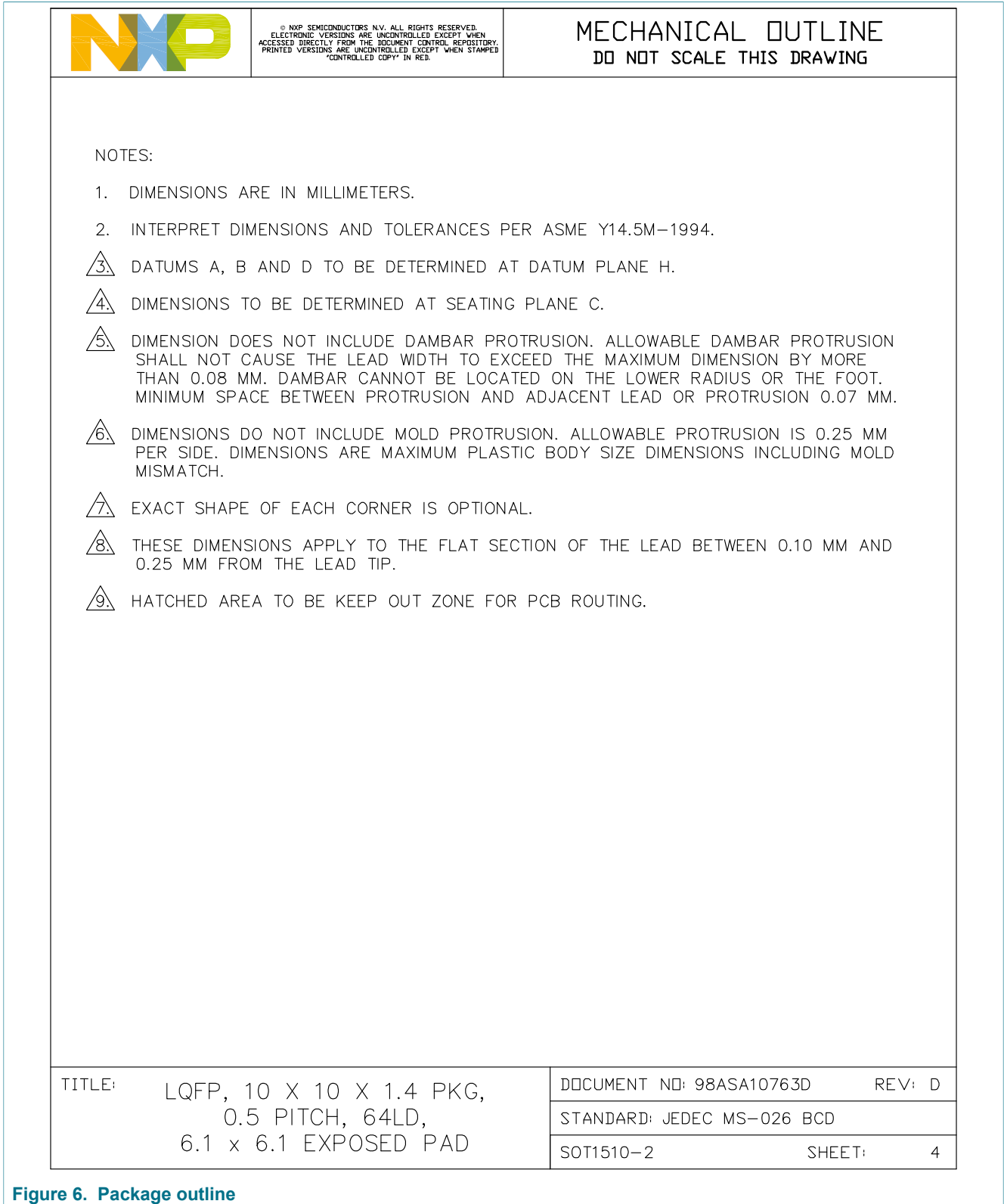


Figure 6. Package outline



## 9 Revision history

**Table 11. Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes
MC33771BSDS v.6.0	20200622	Product data sheet	—	MC33771BSDS v.5.0
Modifications:	Updated to align with full data sheet, MC33771B v.6.0			
MC33771BSDS v.5.0	20180502	Technical data	—	MC33771BSDS v.1
Modifications:	Updated to align with full data sheet, MC33771B v.5.0			
MC33771BSDS v.1	20180419	Product preview	—	—

## 10 Legal information

### 10.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

### 10.2 Definitions

**Draft** — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

**Short data sheet** — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

**Product specification** — The information and data provided in a Product data sheet shall define the specification of the product as agreed between NXP Semiconductors and its customer, unless NXP Semiconductors and customer have explicitly agreed otherwise in writing. In no event however, shall an agreement be valid in which the NXP Semiconductors product is deemed to offer functions and qualities beyond those described in the Product data sheet.

### 10.3 Disclaimers

**Limited warranty and liability** — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information. NXP Semiconductors takes no responsibility for the content in this document if provided by an information source outside of NXP Semiconductors. In no event shall NXP Semiconductors be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory. Notwithstanding any damages that customer might incur for any reason whatsoever, NXP Semiconductors' aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the Terms and conditions of commercial sale of NXP Semiconductors.

**Right to make changes** — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without

notice. This document supersedes and replaces all information supplied prior to the publication hereof.

**Applications** — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification. Customers are responsible for the design and operation of their applications and products using NXP Semiconductors products, and NXP Semiconductors accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the NXP Semiconductors product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products. NXP Semiconductors does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using NXP Semiconductors products in order to avoid a default of the applications and the products or of the application or use by customer's third party customer(s). NXP does not accept any liability in this respect.

**Limiting values** — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) will cause permanent damage to the device. Limiting values are stress ratings only and (proper) operation of the device at these or any other conditions above those given in the Recommended operating conditions section (if present) or the Characteristics sections of this document is not warranted. Constant or repeated exposure to limiting values will permanently and irreversibly affect the quality and reliability of the device.

**Terms and conditions of commercial sale** — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at <http://www.nxp.com/profile/terms>, unless otherwise agreed in a valid written individual agreement. In case an individual agreement is concluded only the terms and conditions of the respective agreement shall apply. NXP Semiconductors hereby expressly objects to applying the customer's general terms and conditions with regard to the purchase of NXP Semiconductors products by customer.

**Suitability for use in automotive applications** — This NXP Semiconductors product has been qualified for use in automotive applications. Unless otherwise agreed in writing, the product is not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors and its suppliers accept no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

**Export control** — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

**Translations** — A non-English (translated) version of a document is for reference only. The English version shall prevail in case of any discrepancy between the translated and English versions.

## 10.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

**SMARTMOS** — is a trademark of NXP B.V.

## Tables

Tab. 1.	Part number breakdown .....	4	Tab. 7.	Maximum ratings .....	9
Tab. 2.	Advanced orderable part table .....	5	Tab. 8.	Thermal ratings .....	11
Tab. 3.	Basic orderable part table .....	5	Tab. 9.	Static and dynamic electrical characteristics ...	11
Tab. 4.	Premium orderable part table .....	5	Tab. 10.	Package Outline .....	20
Tab. 5.	Pin definitions .....	6	Tab. 11.	Revision history .....	25
Tab. 6.	Ratings vs. operating requirements .....	9			

## Figures

Fig. 1.	Simplified application diagram, SPI use case ....	2	Fig. 4.	Low-voltage SPI interface timing .....	19
Fig. 2.	Simplified application diagram, TPL use case .....	3	Fig. 5.	Transformer communication signaling .....	19
Fig. 3.	Pinout diagram .....	6	Fig. 6.	Package outline .....	24